

Notice of References Cited	Application/Control No. 09/550,649	Applicant(s)/Patent Under Reexamination GUERTIN ET AL.	
	Examiner David S. Kim	Art Unit 2613	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,998,069	03-1991	Nguyen et al.	324/539
*	B	US-6,606,354 B1	08-2003	Bach et al.	375/224
*	C	US-7,181,138 B1	02-2007	Gerstel et al.	398/33
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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	U	Hoogerbrugge, M. "Optimizing test strategies for SONET/SDH/ATM network element manufacturing." International Test Conference, 1995. Proceedings. 21-25 October 1995: 973-978.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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